

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at www.onsemi.com

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, emplo



August 2015

FCPF650N80Z

N-Channel SuperFET® II MOSFET

800 V, 10 A, 650 mΩ

Features

- $R_{DS(on)} = 530 \text{ m}\Omega \text{ (Typ.)}$
- Ultra Low Gate Charge (Typ. Q_g = 27 nC)
- Low E_{oss} (Typ. 2.8 uJ @ 400V)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 124 pF)
- 100% Avalanche Tested
- · RoHS Compliant
- · ESD Improved Capability

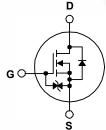
Applications

- AC DC Power Supply
- · LED Lighting

Description

SuperFET® II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. In addition, internal gate-source ESD diode allows to withstand over 2kV HBM surge stress. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as Audio, Laptop adapter, Lighting, ATX power and industrial power applications.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FCPF650N80Z	Unit	
V _{DSS}	Drain to Source Voltage			800	V	
V _{GSS}	Cata ta Carraga Valtaga	- DC		±20	V	
	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V	
I _D	Drain Current	- Continuous (T _C = 25°C)		10*	^	
	Drain Current	- Continuous (T _C = 100°C)		6.3*	A	
I _{DM}	Drain Current	- Pulsed	(Note 1)	24*	Α	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	204	mJ	
I _{AR}	Avalanche Current		(Note 1)	1.6	Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	0.305	mJ	
	MOSFET dv/dt		100	\ //		
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns	
D	Davies Dissination	(T _C = 25°C)		30.5	W	
P_{D}	Power Dissipation - Derate Above 25°C			0.24	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	οС	
T _L	Maximum Lead Temperature for	Soldering, 1/8" from Case for 5 Sec	conds	300	οС	

^{*}Drain current limited by maximum junction temperature, with heatsink.

Thermal Characteristics

Symbol	Parameter	FCPF650N80Z	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	4.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	- 0/00

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCPF650N80Z	FCPF650N80Z	TO-220F	Tube	N/A	N/A	50 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	eteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	800	-	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C	-	0.8	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 800 V, V _{GS} = 0 V	-	-	25	^
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	250	μΑ
I_{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	ı	-	±10	μΑ

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 0.8 \text{ mA}$	2.5	-	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 4 A	-	530	650	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 4 A	-	7.8	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 400 V V 0 V	-	1178	1565	pF
C _{oss}	Output Capacitance	V _{DS} = 100 V, V _{GS} = 0 V, f = 1 MHz	-	36	48	pF
C _{rss}	Reverse Transfer Capacitance	- 1 - 1 IVII IZ	- \	0.84	-	pF
C _{oss}	Output Capacitance	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	18	-	pF
C _{oss (eff.)}	Effective Output Capacitance	$V_{DS} = 0 \text{ V to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	124	-	pF
Q _{g(tot)}	Total Gate Charge at 10V	V _{DS} = 640 V, I _D = 8 A,	-	27	35	nC
Q _{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	6	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	11	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	1.9	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	17	44	ns
t _r		$V_{DD} = 400 \text{ V}, I_D = 8 \text{ A},$	- /	11	32	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_g = 4.7 Ω	-/	40	90	ns
t _f	Turn-Off Fall Time	(Note 4)	- /-	3.4	17	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	10	Α
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	24	Α
V_{SD}	Drain to Source Diode Forward Voltage V	/ _{GS} = 0 V, I _{SD} = 8 A	-	-	1.2	V
t _{rr}	Reverse Recovery Time V	/ _{GS} = 0 V, I _{SD} = 8 A,	-	365	-	ns
Q _{rr}	Reverse Recovery Charge d	II _F /dt = 100 A/μs	-	5.9	-	μС

^{1.} Repetitive rating: pulse width limited by maximum junction temperature.

^{2.} I_{AS} = 1.6 A, R_G = 25 Ω , Starting T_J = 25°C

^{3.} $I_{SD} \le 10$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C

^{4.} Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

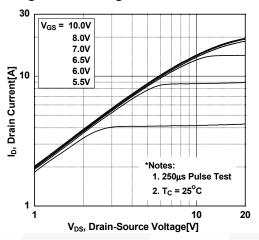


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

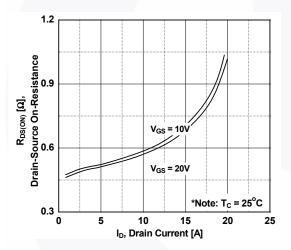


Figure 5. Capacitance Characteristics

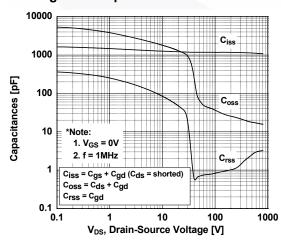


Figure 2. Transfer Characteristics

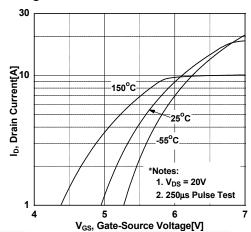


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

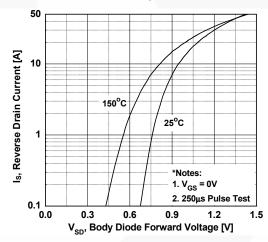
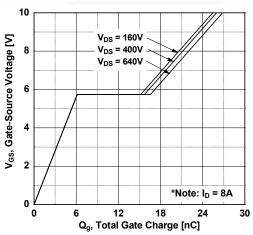


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

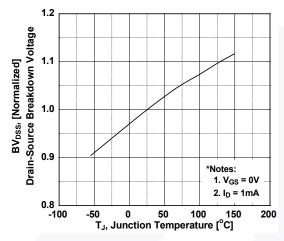


Figure 9. Maximum Safe Operating Area

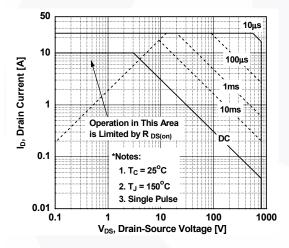


Figure 11. Eoss vs. Drain to Source Voltage

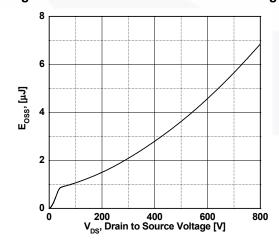


Figure 8. On-Resistance Variation vs. Temperature

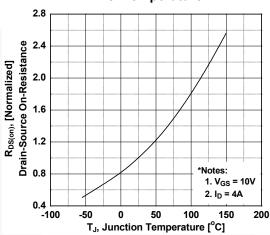
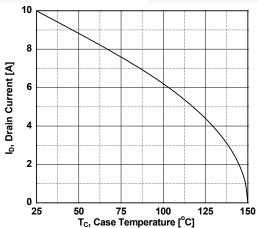
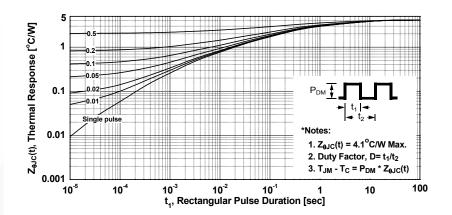


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve



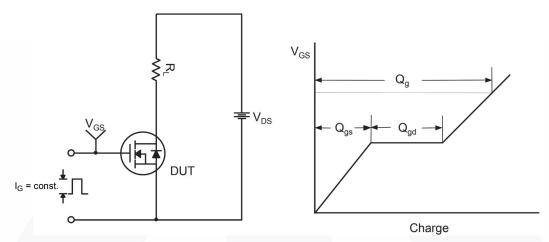


Figure 13. Gate Charge Test Circuit & Waveform

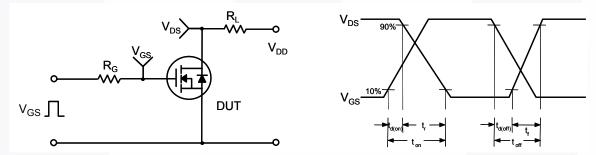


Figure 14. Resistive Switching Test Circuit & Waveforms

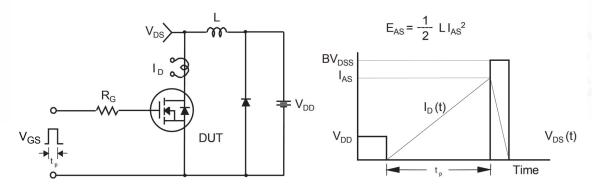


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

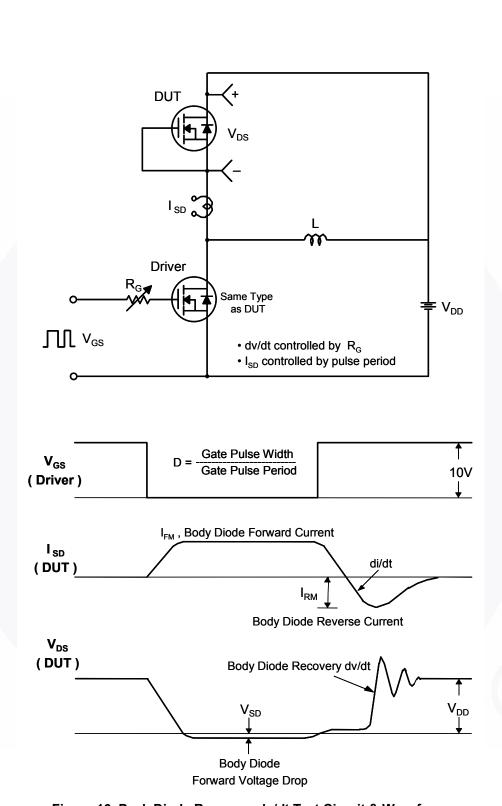
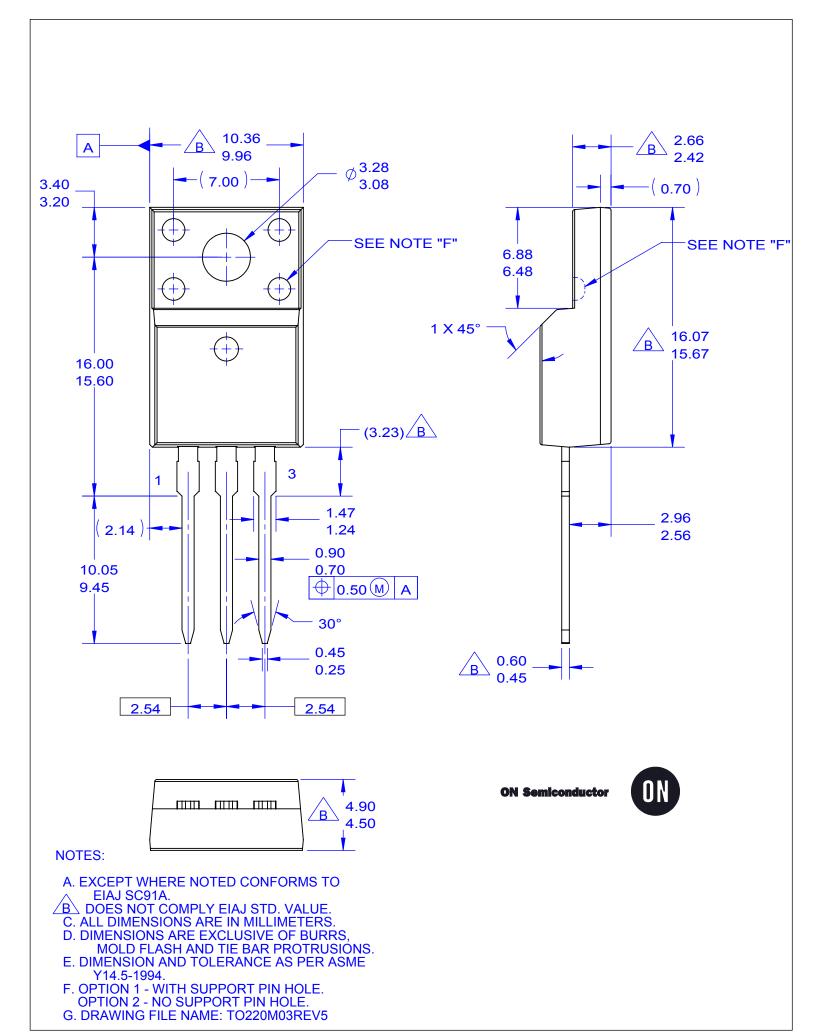


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms



ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support:
Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative